



**UF830-F**

*Power MOSFET*

**4.5A, 500V, 1.5Ω, N-CHANNEL POWER MOSFET**

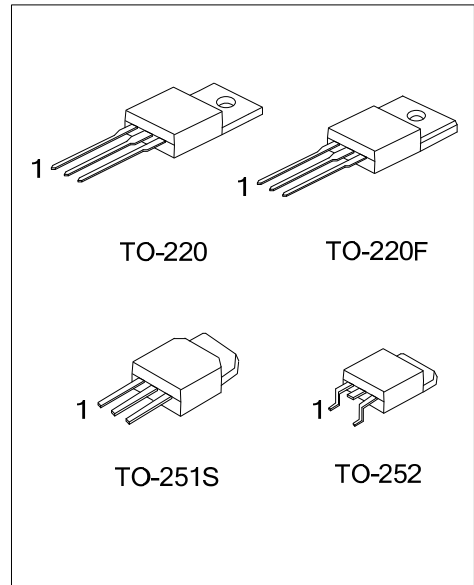
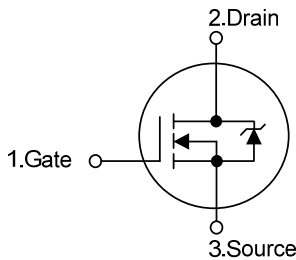
■ **DESCRIPTION**

The N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as switching regulators, switching converters, solenoid, motor drivers, relay drivers.

■ **FEATURES**

- \*  $R_{DS(ON)} < 1.5\Omega @ V_{GS}=10V, I_D=2.5A$
- \* Single Pulse Avalanche Energy Rated
- \* Rugged- SOA is Power Dissipation Limited
- \* Fast Switching Speeds
- \* Linear Transfer Characteristics
- \* High Input Impedance

■ **SYMBOL**



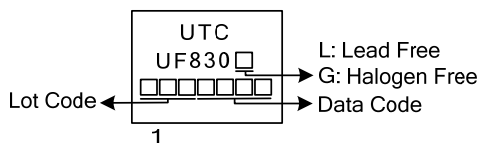
■ **ORDERING INFORMATION**

Ordering Number		Package	Pin Assignment			Packing
Lead Free	Halogen Free		1	2	3	
UF830L-TA3-T	UF830G-TA3-T	TO-220	G	D	S	Tube
UF830L-TF3-T	UF830G-TF3-T	TO-220F	G	D	S	Tube
UF830L-TMS-T	UF830G-TMS-T	TO-251S	G	D	S	Tube
UF830L-TN3-R	UF830G-TN3-R	TO-252	G	D	S	Tape Reel

Note: Pin Assignment: G: Gate D: Drain S: Source

<p>UF830L-TA3-T</p> <p>(1)Packing Type (2)Package Type (3)Green Package</p>	<p>(1) T: Tube, R: Tape Reel (2) TA3: TO-220, TF3: TO-220F, TMS: TO-251S TN3: TO-252 (3) L: Lead Free, G: Halogen Free and Lead Free</p>
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■ **MARKING**



## ■ ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25°C, Unless Otherwise Specified.)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain to Source Voltage (T <sub>J</sub> =25°C ~125°C)		V <sub>DS</sub>	500	V
Drain to Gate Voltage (R <sub>GS</sub> =20kΩ, T <sub>J</sub> =25°C ~125°C)		V <sub>DGR</sub>	500	V
Gate to Source Voltage		V <sub>GS</sub>	±30	V
Drain Current	Continuous	I <sub>D</sub>	4.5	A
	Pulsed	I <sub>DM</sub>	18	A
Power Dissipation (T <sub>C</sub> = 25°C)	TO-220	P <sub>D</sub>	73	W
	TO-220F		38	W
	TO-251S/TO-252		46	W
Single Pulse Avalanche Energy Rating (Note 2)		E <sub>AS</sub>	300	mJ
Junction Temperature		T <sub>J</sub>	+150	°C
Storage Temperature		T <sub>STG</sub>	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

2. V<sub>DD</sub>=50V, starting T<sub>J</sub>=25°C, L=25mH, R<sub>G</sub>=25Ω, peak I<sub>AS</sub>=4.5A

## ■ THERMAL DATA

PARAMETER		SYMBOL	RATINGS	UNIT
Junction to Ambient	TO-220	θ <sub>JA</sub>	62.5	°C/W
	TO-220F		62.5	°C/W
	TO-251S/TO-252		100.3	°C/W
Junction to Case	TO-220	θ <sub>JC</sub>	1.71	°C/W
	TO-220F		3.31	°C/W
	TO-251S/TO-252		2.7	°C/W

## ■ ELECTRICAL SPECIFICATIONS (T<sub>A</sub> =25°C, unless otherwise specified.)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	500			V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250μA	2.0		4.0	V
On-State Drain Current (Note 1)	I <sub>D(ON)</sub>	V <sub>DS</sub> >I <sub>D(ON)</sub> ×R <sub>DS(ON)MAX</sub> , V <sub>GS</sub> =10V	4.5			A
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> = Rated BV <sub>DSS</sub> , V <sub>GS</sub> =0V			25	μA
		V <sub>DS</sub> =0.8×Rated BV <sub>DSS</sub> V <sub>GS</sub> =0V, T <sub>J</sub> = 125°C			250	μA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±30V			±100	nA
Static Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	I <sub>D</sub> =2.5A, V <sub>GS</sub> =10V (Note 2)		1.1	1.5	Ω
Forward Transconductance (Note 1)	g <sub>FS</sub>	V <sub>DS</sub> ≥10V, I <sub>D</sub> =2.7A	2.5	4.2		S
Turn-On Delay Time	t <sub>D(ON)</sub>	V <sub>DD</sub> =30V, I <sub>D</sub> ≈ 0.5A R <sub>GS</sub> =25Ω		38	60	ns
Turn-On Rise Time	t <sub>R</sub>			36	50	ns
Turn-Off Delay Time	t <sub>D(OFF)</sub>			155	170	ns
Turn-Off Fall Time	t <sub>F</sub>			70	90	ns

Notes: 1. Pulse Test: Pulse width≤300μs, Duty Cycle≤2%.

2. MOSFET Switching Times are Essentially Independent of Operating Temperature.

3. Gate Charge is Essentially Independent of Operating Temperature.

### ■ ELECTRICAL SPECIFICATIONS(Cont.) (T<sub>A</sub> =25°C, unless otherwise specified.)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Total Gate Charge	Q <sub>G</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =1.3A		21	30	nC
Gate-Source Charge	Q <sub>GS</sub>	V <sub>DS</sub> =0.8×Rated BV <sub>DSS</sub>		5.2		nC
Gate-Drain Charge	Q <sub>GD</sub>	I <sub>G(REF)</sub> =100μA (Note 3)		5.6		nC
Input Capacitance	C <sub>ISS</sub>	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V, f=1.0MHz		600		pF
Output Capacitance	C <sub>OSS</sub>			78		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>			15		pF

Notes: 1. Pulse Test: Pulse width≤300μs, Duty Cycle≤2%.

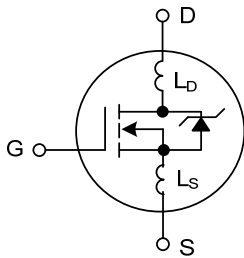
2. MOSFET Switching Times are Essentially Independent of Operating Temperature.

3. Gate Charge is Essentially Independent of Operating Temperature.

### ■ INTERNAL PACKAGE INDUCTANCE

PARAMETER	SYMBOL	MIN	TYP	MAX	UNIT
<b>Internal Drain Inductance</b>					
Measured from the contact screw on tab to center of die	L <sub>D</sub>		3.5		nH
Measured from the drain lead(6mm from package) to center of die			4.5		nH
<b>Internal Source Inductance</b>					
Measured from the source lead(6mm from header) to source bond pad	L <sub>S</sub>		7.5		nH

Remark: Modified MOSFET symbol showing the internal devices inductances as below.

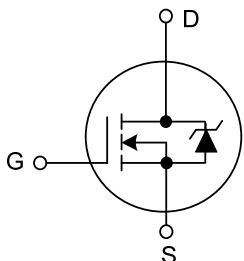


### ■ SOURCE TO DRAIN DIODE SPECIFICATIONS

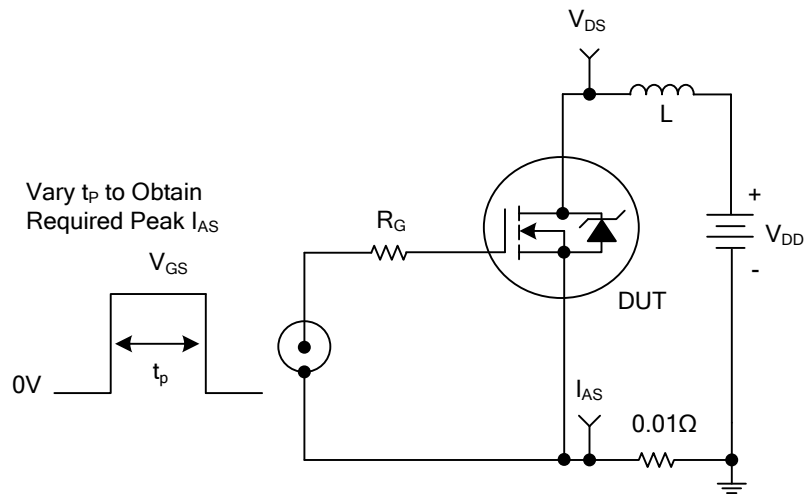
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Source to Drain Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> =25°C, I <sub>SD</sub> =4.5A, V <sub>GS</sub> =0V(Note 1)			1.6	V
Continuous Source to Drain Current	I <sub>SD</sub>	Note 2			5.5	A
Pulse Source to Drain Current	I <sub>SDM</sub>				18	A
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> =25°C, I <sub>SD</sub> =4.5A, dI/dt=100A/μs	180	350	760	ns
Reverse Recovery Charge	Q <sub>RR</sub>	T <sub>J</sub> =25°C, I <sub>SD</sub> =4.5A, dI/dt=100A/μs	0.96	2.2	4.3	μC

Notes: 1. Pulse Test: Pulse width≤300μs, Duty Cycle≤2%.

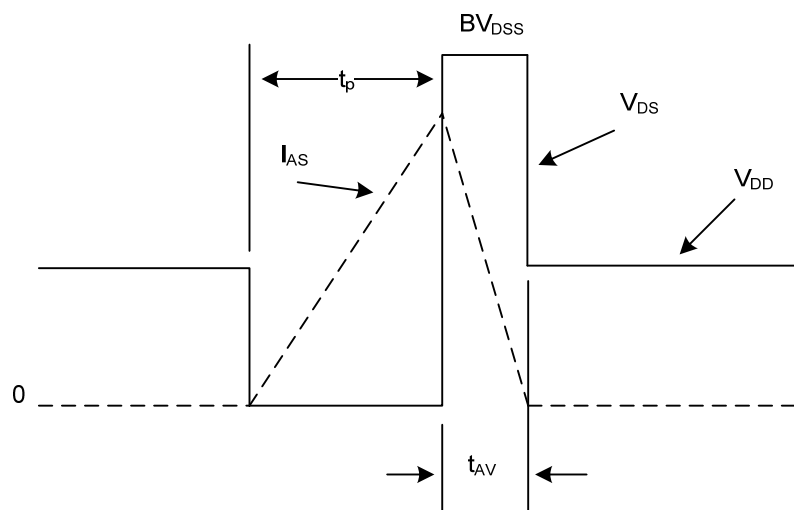
2. Modified MOSFET symbol showing the integral reverse P-N junction diode as below.



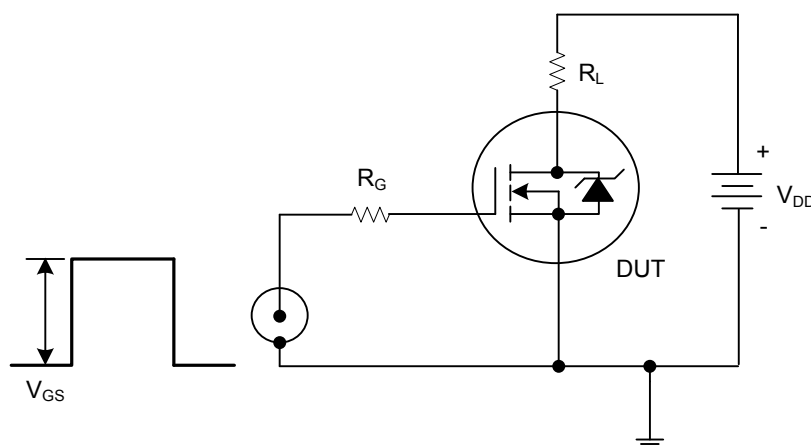
■ TEST CIRCUITS AND WAVEFORMS



Unclamped Energy Test Circuit

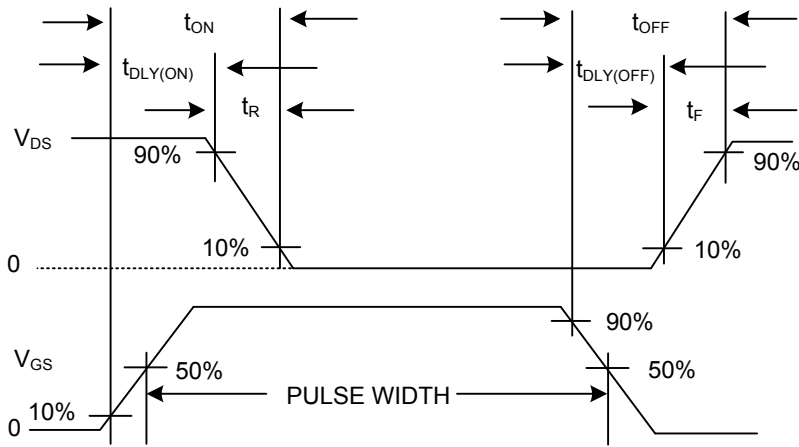


Unclamped Energy Waveforms

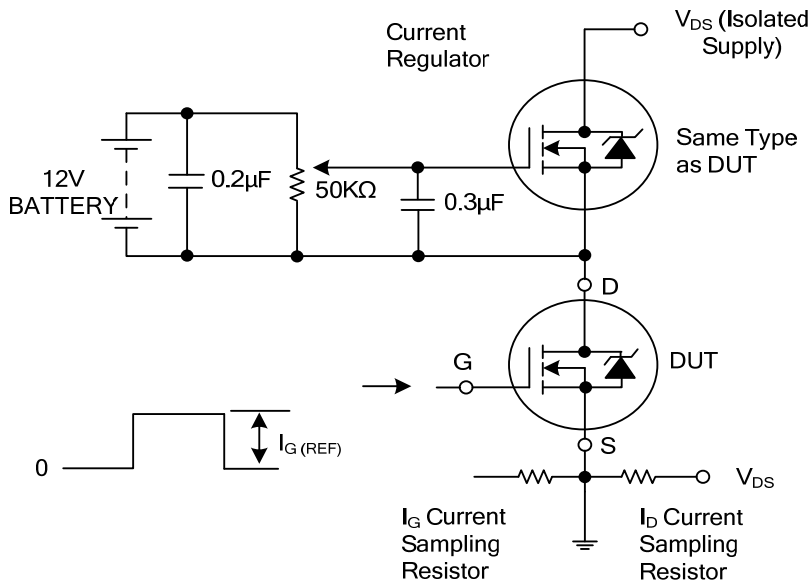


Switching Time Test Circuit

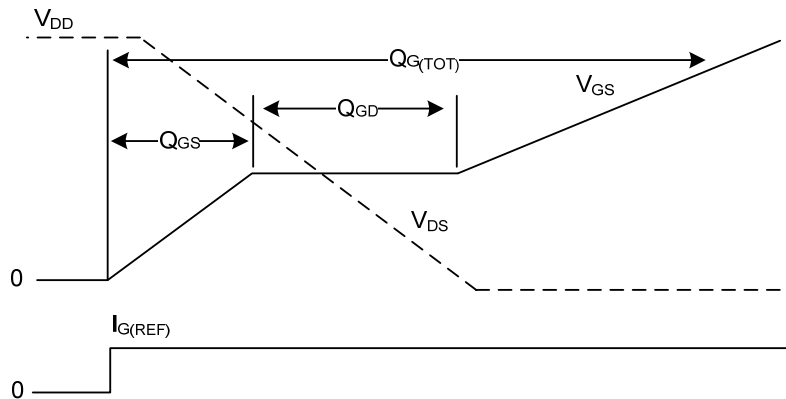
■ TEST CIRCUITS AND WAVEFORMS (Cont.)



Resistive Switching Waveforms



Gate Charge Test Circuit



Gate Charge Waveforms

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